

Notice of References Cited		Application/Control No. 09/943,209	Applicant(s)/Patent Under Reexamination LAM ET AL.	
		Examiner Tuan A Vu	Art Unit 2124	Page 1 of 1

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NON-PATENT DOCUMENTS

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	U	Zambelich, K., "Totally Data-driven Automated Testing", copyright 1998, White Paper, < http://www.dkl.com/pdf/datadriven.pdf > or < http://www.sqa-test.com/w_paper1.html >
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	X	

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